

**Search Notes**

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Examiner

Michael J. Hayes

Applicant(s)/Patent under  
Reexamination

FURTH ET AL.

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
(604/68-72,522 435/285.1,285.3,455,459 600/104 606/119) updated search - see search history	3/11/2006	MJH